TOSHIBA Field Effect Transistor Silicon N-Channel MOS Type ( $\pi$  –MOS VI)

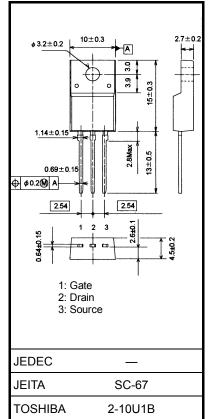
# 2SK4015

### Switching Regulator Applications

- Low drain-source ON-resistance: RDS (ON) = 0.60  $\Omega$  (typ.)
- High forward transfer admittance:  $|Y_{fs}| = 7.4 \text{ S}$  (typ.)
- Low leakage current:  $I_{DSS} = 100 \ \mu A (V_{DS} = 600 \text{ V})$
- Enhancement model:  $V_{th} = 2.0 \sim 4.0 \text{ V} (V_{DS} = 10 \text{ V}, \text{ID} = 1 \text{ mA})$

### Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
Drain-source voltage		V <sub>DSS</sub>	600	V	
Drain-gate voltage (F	R <sub>GS</sub> = 20 kΩ)	V <sub>DGR</sub>	600	V	
Gate-source voltage		V <sub>GSS</sub>	±30	V	
Drain current	DC (Note 1)	Ι <sub>D</sub>	10		
	Pulse (t = 1 ms) (Note 1)	I <sub>DP</sub>	40	A	
Drain power dissipati	on (Tc = 25°C)	PD	45	W	
Single-pulse avalanc	he energy (Note 2)	E <sub>AS</sub>	363	mJ	
Avalanche current		I <sub>AR</sub>	10	А	
Repetitive avalanche	energy (Note 3)	E <sub>AR</sub>	4.5	mJ	
Channel temperature	9	T <sub>ch</sub>	150	°C	
Storage temperature range		T <sub>stg</sub>	-55~150	°C	



Weight: 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

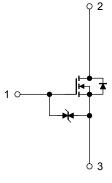
### **Thermal Characteristics**

Characteristic	Symbol	Мах	Unit	
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	2.78	°C/W	
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W	

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 6.36 mH, I<sub>AR</sub> = 10 A, R<sub>G</sub> = 25  $\Omega$ 

This transistor is an electrostatic-sensitive device. Handle with care.



Unit: mm

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

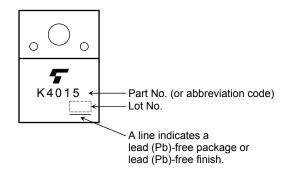
**Electrical Characteristics (Ta = 25°C)** 

Char	acteristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage current		I <sub>GSS</sub>	$V_{GS}=\pm 25~V,~V_{DS}=0~V$		_	±10	μA
Gate-source breakdown voltage		V (BR) GSS	$I_G=\pm 10~\mu\text{A},~V_{DS}=0~\text{V}$	±30	_		V
Drain cutoff curre	ent	IDSS	$V_{DS} = 600 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	_	_	100	μA
Drain-source bre	akdown voltage	V (BR) DSS	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}$	600	_		V
Gate threshold v	oltage	V <sub>th</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 1 \text{ mA}$	2.0	_	4.0	V
Drain-source ON	-resistance	R <sub>DS (ON)</sub>	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$	_	0.60	0.86	Ω
Forward transfer	admittance	Y <sub>fs</sub>	$V_{DS} = 10 \text{ V}, \text{ I}_{D} = 5 \text{ A}$	3.7	7.4		S
Input capacitance		C <sub>iss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz		1500		pF
Reverse transfer capacitance		C <sub>rss</sub>			15		
Output capacitance		C <sub>oss</sub>			180		
Switching time	Rise time	tr	$V_{GS}$ $0 V$ $V_{DD} \simeq 200 V$ $V_{DD} \simeq 200 V$	_	22		
	Turn-on time	t <sub>on</sub>		_	50	_	
	Fall time	t <sub>f</sub>		_	36	_	ns
	Turn-off time	t <sub>off</sub>	Duty $\leq$ 1%, t <sub>w</sub> = 10 $\mu$ s	_	180	_	
Total gate charge		Qg		_	42		
Gate-source charge		Q <sub>gs</sub>	$V_{DD}\simeq 400~V,~V_{GS}=10~V,~I_{D}=10~A$	_	23		nC
Gate-drain charge		Q <sub>gd</sub>	]	_	19		

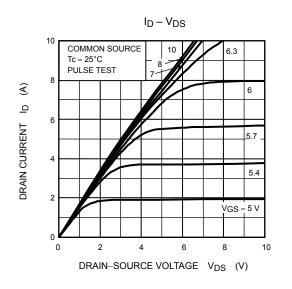
# Source-Drain Ratings and Characteristics (Ta = 25°C)

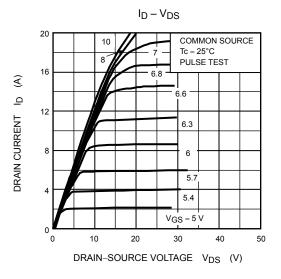
Characteristic	Symbol	Test Condition	Min	Тур.	Мах	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	—	_	_	10	А
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	—	_	_	40	А
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 10 A, V <sub>GS</sub> = 0 V	_	_	-1.7	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 10 A, V <sub>GS</sub> = 0 V,	_	170	_	ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> /dt = 100 A/μs		0.6	_	μC

# Marking

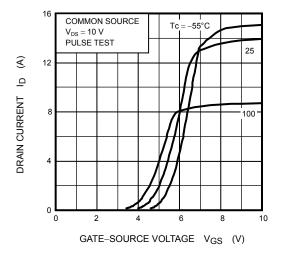


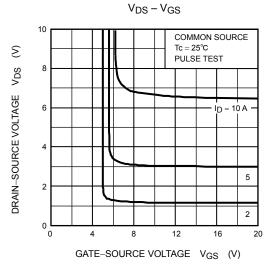
# <u>TOSHIBA</u>



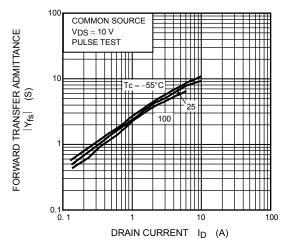




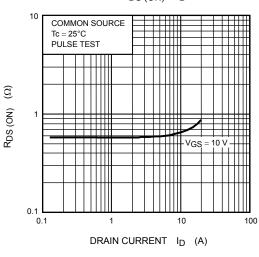




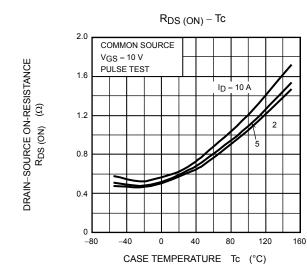


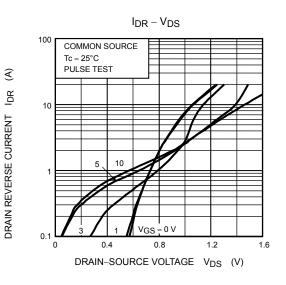


 $R_{DS(ON)} - I_D$ 

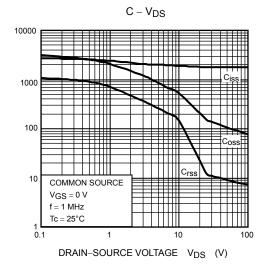


DRAIN-SOURCE ON-RESISTANCE

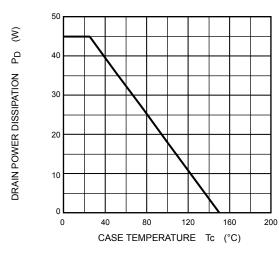


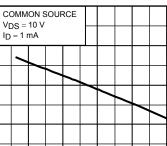


CAPACITANCE C (pF)









 $V_{th} - Tc$ 

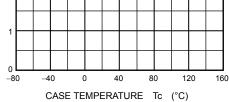
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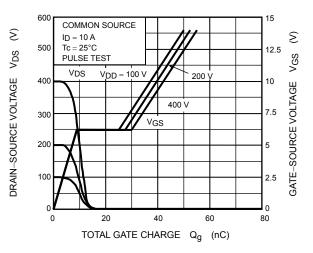
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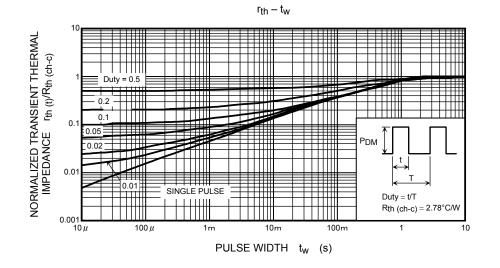
V<sub>th</sub> (V)

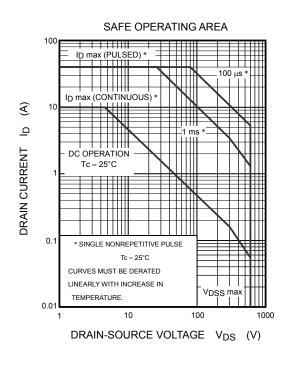
GATE THRESHOLD VOLTAGE

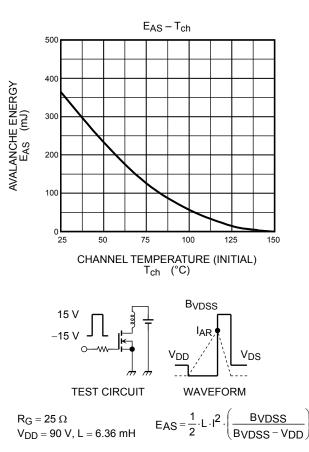












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